Application/Control No. O9/665,177 Notice of References Cited Application/Control No. O9/665,177 Examiner Hai C Pham Application/Control No. Applicant(s)/Patent Under Reexamination SHIRAISHI ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,815,301	09-1998	Naiki et al.	359/205
	В	US-5,745,277	04-1998	Boku et al.	359/207
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			·
	к	US-			
	L	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*	_	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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